

April 2001 Revised April 2002

FIN1017

3.3V LVDS 1-Bit High Speed Differential Driver

General Description

This single driver is designed for high speed interconnects utilizing Low Voltage Differential Signaling (LVDS) technology. The driver translates LVTTL signal levels to LVDS levels with a typical differential output swing of 350 mV which provides low EMI at ultra low power dissipation even at high frequencies. This device is ideal for high speed transfer of clock or data.

The FIN1017 can be paired with its companion receiver, the FIN1018, or with any other LVDS receiver.

Features

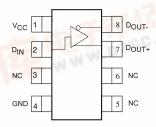
- Greater than 600Mbs data rate
- 3.3V power supply operation
- 0.5ns maximum differential pulse skew
- 1.5ns maximum propagation delay
- Low power dissipation
- Power-Off protection
- Meets or exceeds the TIA/EIA-644 LVDS standard
- Flow-through pinout simplifies PCB layout
- 8-Lead SOIC and US8 packages save space

Ordering Code:

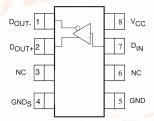
| Order Number | Package Number | Package Description | | |
|--------------|---|--|--|--|
| FIN1017M | | 8-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow [TUBE] | | |
| FIN1017MX | 7MX M08A 8-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" N [TAPE and REEL] | | | |
| FIN1017K8X | MAB08A | 8-Lead US8, JEDEC MO-187, Variation CA 3.1mm Wide [TAPE and REEL] | | |

Connection Diagrams

8-Lead SOIC



Pin Assignment for US-8 Package



Note: Ground pins 4 and 5 for optimum operation.

TOP VIEW

Pin Descriptions

| Pin Name | Description | | |
|--------------------|-----------------------------|--|--|
| D _{IN} | LVTTL Data Input | | |
| D _{OUT+} | Non-inverting Driver Output | | |
| D _{OUT} - | Inverting Driver Output | | |
| V _{CC} | Power Supply | | |
| GND | Ground | | |
| NC | No Connect | | |

Function Table

| Input | Outputs | | |
|-----------------|-------------------|------------------|--|
| D _{IN} | D _{OUT+} | D _{OUT} | |
| L | L | Н | |
| Н | Н | L | |
| OPEN | L | Н | |

H = HIGH Logic Level L = LOW Logic Level X = Don't Care

Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

Supply Voltage (V_{CC}) -0.5V to +4.6V DC Input Voltage (DIN) -0.5V to +6V

DC Output Voltage (D_{OUT}) -0.5V to +4.7VDriver Short Circuit Current (I_{OSD}) Continuous

Storage Temperature Range (T_{STG}) -65°C to +150°C 150°C

Max Junction Temperature (T_{.1})

Lead Temperature (T_L)

(Soldering, 10 seconds) 260°C ESD (Human Body Model) ≥ 6500V ESD (Bus Pins D_{OUT+}/D_{OUT-} to GND) ≥ 10500V

ESD (Machine Model) ≥ 350V Supply Voltage (V_{CC}) 3.0V to 3.6V Input Voltage (V_{IN}) 0 to $V_{\rm CC}$ Operating Temperature (T_A) -40°C to $+85^{\circ}\text{C}$

Note 1: The "Absolute Maximum Ratings": are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature and output/input loading variables. Fairchild does not recommend operation of circuits outside databook specification.

DC Electrical Characteristics

Over supply voltage and operating temperature ranges, unless otherwise specified

| Symbol | Parameter | Test Conditions | Min | Typ (Note 2) | Max | Units |
|---------------------|---------------------------------------|--|-------|-----------------|-----------------|-------|
| V _{OD} | Output Differential Voltage | | 250 | 350 | 450 | mV |
| ΔV_{OD} | V _{OD} Magnitude Change from | | | | 25 | mV |
| | Differential LOW-to-HIGH | $R_{I} = 100 \Omega$, See Figure 1 | | | | |
| Vos | Offset Voltage | N_ = 100 12, 000 1 iguio 1 | 1.125 | 1.25 | 1.375 | V |
| ΔV_{OS} | Offset Magnitude Change from | | | | 25 | mV |
| | Differential LOW-to-HIGH | | | | 25 | 1117 |
| l _{OFF} | Power-Off Output Current | $V_{CC} = 0V, V_{OUT} = 0V \text{ or } 3.6V$ | | | ±20 | μΑ |
| los | Short Circuit Output Current | V _{OUT} = 0V | | | -8 | mA |
| | | $V_{OD} = 0V$ | | | ±8 | |
| V _{IH} | Input HIGH Voltage | | 2.0 | | V _{CC} | V |
| V _{IL} | Input LOW Voltage | | GND | | 0.8 | V |
| I _{IN} | Input Current | V _{IN} = 0V or V _{CC} | | | ±20 | μΑ |
| I _{I(OFF)} | Power-Off Input Current | V _{CC} = 0V, V _{IN} = 0V or 3.6V | | | ±20 | μΑ |
| V _{IK} | Input Clamp Voltage | I _{IK} = -18 mA | -1.5 | | | V |
| I _{CC} | Power Supply Current | No Load, V _{IN} = 0V or V _{CC} | | | 8 | mA |
| | | $R_L = 100 \Omega$, $V_{IN} = 0V$ or V_{CC} | | | 10 | mA |
| C _{IN} | Input Capacitance | | | 4 | | pF |
| C _{OUT} | Output Capacitance | | | 6 | | pF |

Note 2: All typical values are at T_A = 25°C and with V_{CC} = 3.3V.

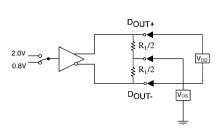
AC Electrical Characteristics

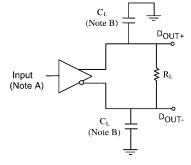
Over supply voltage and operating temperature ranges, unless otherwise specified

| Symbol | Parameter | Test Conditions | Min | Typ (Note 3) | Max | Units |
|---------------------|---|--------------------------------------|-----|-----------------|-----|-------|
| t _{PLHD} | Differential Propagation Delay | | 0.5 | | 1.5 | ns |
| | LOW-to-HIGH | | 0.5 | | 1.5 | 115 |
| t _{PHLD} | Differential Propagation Delay | $R_L = 100 \ \Omega, \ C_L = 10 pF,$ | 0.5 | | 1.5 | ns |
| | HIGH-to-LOW | | | | | |
| t _{TLHD} | Differential Output Rise Time (20% to 80%) | See Figure 2 and Figure 3 | 0.4 | | 1.0 | ns |
| t _{THLD} | Differential Output Fall Time (80% to 20%) | | 0.4 | | 1.0 | ns |
| t _{SK(P)} | Pulse Skew t _{PLH} - t _{PHL} | | | | 0.5 | ns |
| t _{SK(PP)} | Part-to-Part Skew (Note 4) | | | | 1.0 | ns |

Note 3: All typical values are at $T_A = 25^{\circ}C$ and with $V_{CC} = 3.3V$.

Note 4: t_{SK(PP)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices switching in the same direction (either LOW-to-HIGH or HIGH-to-LOW) when both devices operate with the same supply voltage, same temperature, and have identical test circuits.





 $\label{eq:Note A: All input pulses have frequency = 10 MHz, } t_R \mbox{ or } t_F = 2 \mbox{ ns}$ $\mbox{Note B: } C_L \mbox{ includes all probe and fixture capacitances}$

FIGURE 1. Differential Driver DC Test Circuit

FIGURE 2. Differential Driver Propagation Delay and Transition Time Test Circuit

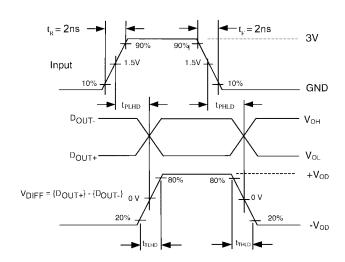
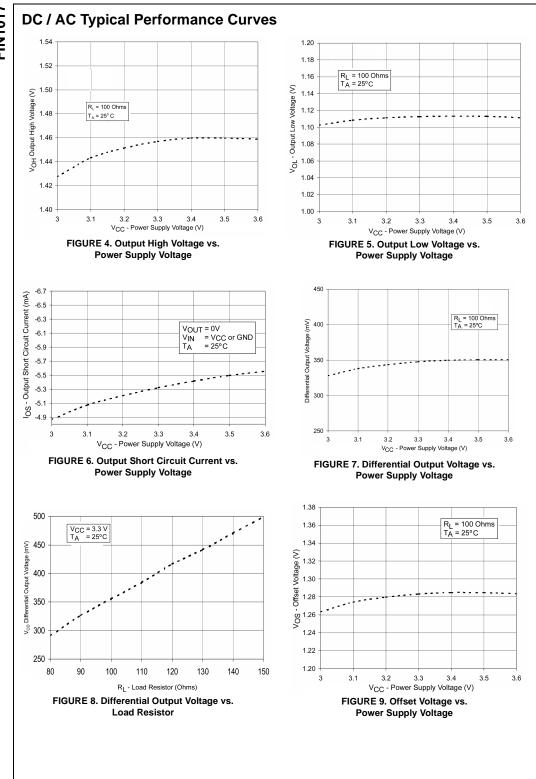
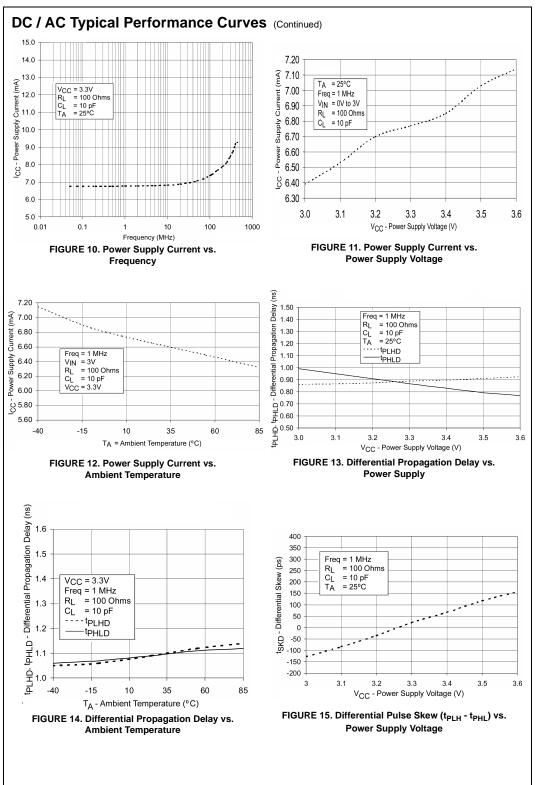


FIGURE 3. AC Waveforms





DC / AC Typical Performance Curves (Continued)

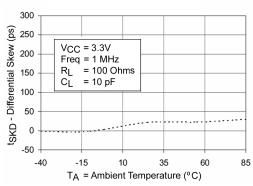


FIGURE 16. Differential Pulse Skew ($t_{\rm PLH}$ - $t_{\rm PHL}$) vs. Ambient Temperature

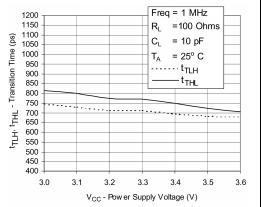


FIGURE 17. Transition Time vs. Power Supply Voltage

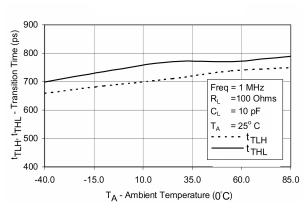
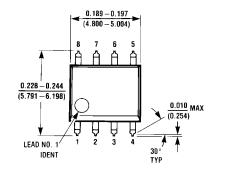
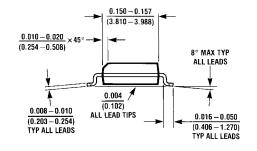
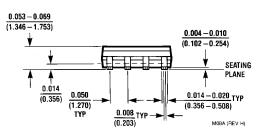


FIGURE 18. Transition Time vs. Ambient Temperature

Physical Dimensions inches (millimeters) unless otherwise noted

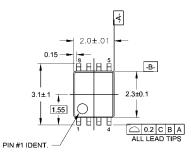


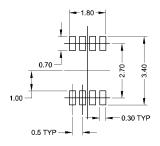




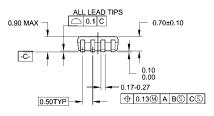
8-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow Package Number M08A

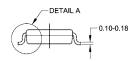
Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

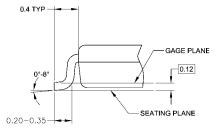




LAND PATTERN RECOMMENDATION







DETAIL A

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-187
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
- D. DIMENSIONS AND TOLERANCES PER ANSI Y14.5M, 1982.

MAB08AREVC

8-Lead US8, JEDEC MO-187, Variation CA 3.1mm Wide Package Number MAB08A

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